Se	arch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/697,558	HAYASHI ET AL.	
Examiner	Art Unit	
Sophia S. Chen	2852	

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	SEARCHED			
Class	Subclass	Date	Examiner	
399	258, 262, 260, 120, 119	3/22/2005	sc	
222	DIG.1	3/22/2005	sc	
above	updated	8/22/2005	sc	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Interfered History Pr	ice Search	8/22/2005	sc
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SEARCH NO (INCLUDING SEARCI		)
	DATE	EXMR
Text Search (see printout)	3/22/2005	SC
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